Se	arch	Notes	•

Application/Control No.	Applicant(s)/Patent und Reexamination		
10/731,722	TRAN ET AL.		
Examiner ,	Art Unit		
David Sample	1755		

SEARCHED				
Class	Subclass	Date	Examiner	
423	700	9/22/2006	PAI	
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502	74		QUI.	
	60	9/22/2006		
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UP	DATED	4/11/2007	PAI	
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Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	. DATE	EXMR
East searched	9/22/2006	SU
STN file CA searched	9/22/2006	W
Inventor name PALM search	9/22/2006	OUI
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